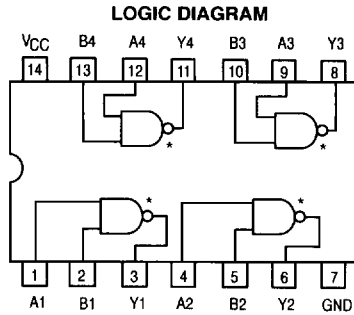




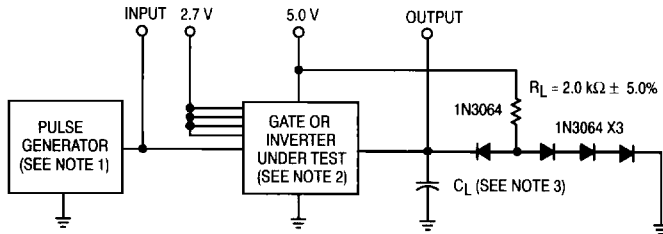
# Quad 2-Input NAND Gate

ELECTRICALLY TESTED PER:  
MIL-M-38510/30002

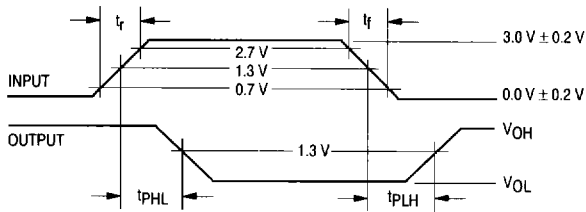


\*OPEN COLLECTOR OUTPUT

### AC TEST CIRCUIT



### WAVEFORMS



#### NOTES:

1. Pulse generator has the following characteristics:  $t_r \leq 15$  ns,  $t_f \leq 6.0$  ns,  $PRR \leq 1.0$  MHz, duty cycle = 50% and  $Z_{OUT} = 50 \Omega$ .
2. Inputs not under test are at 2.7 V.
3.  $C_L = 50$  pF  $\pm 10\%$ , including scope probe, wiring and stray capacitance.
4.  $R_L = 2.0$  k $\Omega \pm 5.0\%$ .
5. Voltage measurements are to be made with respect to network ground terminal.

## Military 54LS03



#### AVAILABLE AS:

- 1) JAN: JM38510/30002BXA
- 2) SMD: N/A
- 3) 883: 54LS03/BXAJC

X = CASE OUTLINE AS FOLLOWS:  
PACKAGE: CERDIP: C  
CERFLAT: D  
LCC: 2

THE LETTER "M" APPEARS  
BEFORE THE / ON LCC.

#### PIN ASSIGNMENTS

FUNCT.	DIL 632-08	FLATS 717-04	LCC 756A-02	BURN-IN (COND. A)
A1	1	1	2	V <sub>CC</sub>
B1	2	2	3	GND
Y1	3	3	4	V <sub>CC</sub>
A2	4	4	6	V <sub>CC</sub>
B2	5	5	8	GND
Y2	6	6	9	V <sub>CC</sub>
GND	7	7	10	GND
Y3	8	8	12	V <sub>CC</sub>
A3	9	9	13	V <sub>CC</sub>
B3	10	10	14	GND
Y4	11	11	16	V <sub>CC</sub>
A4	12	12	18	V <sub>CC</sub>
B4	13	13	19	GND
V <sub>CC</sub>	14	14	20	V <sub>CC</sub>

#### BURN-IN CONDITIONS:

V<sub>CC</sub> = 5.0 V MIN/6.0 V MAX

#### TRUTH TABLE

A	B	Y
0	0	1
0	1	1
1	0	1
1	1	0

## 54LS03

Symbol	Parameter	Limits						Unit	Test Condition (Unless Otherwise Specified)
		+ 25°C		+ 125°C		- 55°C			
		Subgroup 1		Subgroup 2		Subgroup 3			
		Min	Max	Min	Max	Min	Max		
V <sub>OL</sub>	Logical "0" Output Voltage		0.4		0.4		0.4	V	V <sub>CC</sub> = 4.5 V, I <sub>OL</sub> = 4.0 mA, V <sub>IH</sub> = 2.0 V on both inputs.
V <sub>IC</sub>	Input Clamping Voltage		-1.5					V	V <sub>CC</sub> = 4.5 V, I <sub>IN</sub> = -18 mA, other input is open.
I <sub>CEX</sub>	Open Collector Input Current		100		100		100	μA	V <sub>CC</sub> = 4.5 V, V <sub>IL</sub> = 0.7 V, V <sub>IH</sub> = 5.5 V on other input, V <sub>OUT</sub> = 5.5 V.
I <sub>IH1</sub>	Logical "1" Input Current		20		20		20	μA	V <sub>CC</sub> = 5.5 V, V <sub>IH</sub> = 2.7 V, other input = 0 V.
I <sub>IH2</sub>	Logical "1" Input Current		100		100		100	μA	V <sub>CC</sub> = 5.5 V, V <sub>IH</sub> = 5.5 V, other input = 0 V.
I <sub>IL</sub>	Logical "0" Input Current	- 150	- 380	- 150	- 380	- 150	- 380	μA	V <sub>CC</sub> = 5.5 V, V <sub>IH</sub> = 0.4 V, other inputs = 5.5 V.
I <sub>CCH</sub>	Power Supply Current		1.6		1.6		1.6	mA	V <sub>CC</sub> = 5.5 V, V <sub>IH</sub> = 0 V (all inputs).
I <sub>CCL</sub>	Power Supply Current		4.4		4.4		4.4	mA	V <sub>CC</sub> = 5.5 V, V <sub>IH</sub> = 5.5 V (all inputs).
V <sub>IH</sub>	Logical "1" Input Voltage	2.0		2.0		2.0		V	V <sub>CC</sub> = 4.5 V.
V <sub>IL</sub>	Logical "0" Input Voltage		0.7		0.7		0.7	V	V <sub>CC</sub> = 4.5 V.
	Functional Tests	Subgroup 7		Subgroup 8A		Subgroup 8B			per Truth Table with V <sub>CC</sub> = 5.0 V, V <sub>INL</sub> = 0.5 V, and V <sub>IH</sub> = 2.5 V.

Symbol	Parameter	Limits						Unit	Test Condition (Unless Otherwise Specified)
		+ 25°C		+ 125°C		- 55°C			
		Subgroup 9		Subgroup 10		Subgroup 11			
		Min	Max	Min	Max	Min	Max		
t <sub>PHL</sub> t <sub>PHL</sub>	Propagation Delay /Data-Output Output High-Low	2.0 —	36 28	2.0 —	55 50	2.0 —	55 50	ns	V <sub>CC</sub> = 5.0 V, C <sub>L</sub> = 50 pF, R <sub>L</sub> = 2.0 kΩ. V <sub>CC</sub> = 5.0 V, C <sub>L</sub> = 15 pF, R <sub>L</sub> = 2.0 kΩ.
t <sub>PLH</sub> t <sub>PLH</sub>	Propagation Delay /Data-Output Output Low-High	2.0 —	40 32	2.0 —	60 55	2.0 —	60 55	ns	V <sub>CC</sub> = 5.0 V, C <sub>L</sub> = 50 pF, R <sub>L</sub> = 2.0 kΩ. V <sub>CC</sub> = 5.0 V, C <sub>L</sub> = 15 pF, R <sub>L</sub> = 2.0 kΩ.

## NOTE:

1. The limits specified for C<sub>L</sub> = 15 pF are guaranteed but not tested.